## What is Claimed Is:

Sub (U)>

10

15

25

1. A semiconductor pressure sensor comprising;

a substrate,

a diaphragm formed on said substrate by sacrificial layer etching method, and

a silicon oxide film provided by sealing the etchant filling hole of the sacrificial layer on the said diaphragm;

said semiconductor pressure sensor characterized in that a polysilicon film is provided to cover part or whole of said silicon oxide film.

- 2. A semiconductor pressure sensor according to Claim 1 characterized in that the distance of said covered part is at least 10 microns or less from said etchant filling hole.
- 3. A semiconductor pressure sensor according to 20 Claim 1 characterized in that the thickness of said polysilicon film is 0.1 microns or more.
  - 4. A semiconductor pressure sensor according to Claim 1 characterized in that the thickness of said polysilicon film is 0.1 microns and over up to and

5

10

15

20

25

including 0.4 microns.

- . A pressure detector comprising;
- (a) a detector further comprising as an integral unit;
  - a substrate,
  - a diaphragm formed on said substrate by sacrificial layer etching method,
  - a silicon oxide film provided by sealing the etchant filling hole of the sacrificial layer on the said diaphragm, and
  - a polysilicon film covering part or whole of said silicon oxide film;
- (b) a correction circuit for correction of the output of said detector;
  - (d) a package enclosing said correction circuit and said detegtor; and
  - (d) an intake tube provided in said package and used for introduction of external pressure to said detector.
  - 6. A pressure detector according to Claim 5 characterized in that (h) the distance of said covered part is at least 10 microns or less from said etchant filling hole.

5

10

15

- 7. A pressure detector according to Claim 5 characterized in that (i) the thickness of said polysilicon film is 0.1 microns or more.
- 8. A pressure detector according to Claim 5 characterized in that (j) the thickness of said polysilicon film is 0.1 microns and over up to and including 0.4 microns.
  - 9. A pressure detector according to Claim 5 comprising:
  - (e) a sub-package further comprising said correction circuit and said detector as an integral unit, and having on the surface a pad connected to said correction circuit, and
  - (f) an output terminal removably connected to the external signal line and used to send a signal from said correction circuit to the external signal line;
- said pressure detector further characterized in that
  - (g) said correction circuit and said detector are enclosed by said package after said pad and said output terminal are connected by a metal wire.